

ABSTRACT

The present invention concerns an apparatus and method for absorbance detection in instrumental situations which have short absorption path lengths,
5 such as microchip type devices. By modulating the sample beam incident upon a sample cell, the sensitivity of the absorbance measurement is improved. The modulation means includes a scanning device arranged to move the sample beam from a first position in which the sample beam is incident upon said sample area to a second position in which the sample beam is incident upon
10 the cell.

Figure 1.